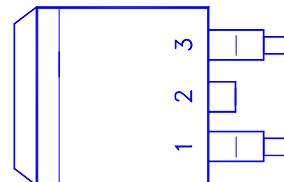
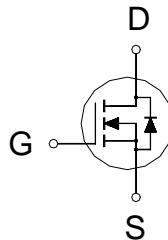


**NIKO-SEM**
**N-Channel Logic Level Enhancement  
Mode Field Effect Transistor**
**P70N02LS**  
**TO-263 (D<sup>2</sup>PAK)**
**PRODUCT SUMMARY**

$V_{(BR)DSS}$	$R_{DS(ON)}$	$I_D$
25	7mΩ	70A

**ABSOLUTE MAXIMUM RATINGS ( $T_C = 25^\circ\text{C}$  Unless Otherwise Noted)**

PARAMETERS/TEST CONDITIONS	SYMBOL	LIMITS	UNITS
Gate-Source Voltage	$V_{GS}$	$\pm 20$	V
Continuous Drain Current	$I_D$	70	A
		45	
Pulsed Drain Current <sup>1</sup>	$I_{DM}$	170	
Avalanche Current	$I_{AR}$	60	
Avalanche Energy	$E_{AS}$	140	mJ
Repetitive Avalanche Energy <sup>2</sup>	$E_{AR}$	5.6	
Power Dissipation	$P_D$	65	W
		38	
Operating Junction & Storage Temperature Range	$T_j, T_{stg}$	-55 to 150	°C
Lead Temperature (1/16" from case for 10 sec.)	$T_L$	275	

**THERMAL RESISTANCE RATINGS**

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Case	$R_{\theta JC}$		2.3	
Junction-to-Ambient	$R_{\theta JA}$		62.5	°C / W
Case-to-Heatsink	$R_{\theta CS}$	0.6		

<sup>1</sup>Pulse width limited by maximum junction temperature.<sup>2</sup>Duty cycle ≤ 1%**ELECTRICAL CHARACTERISTICS ( $T_C = 25^\circ\text{C}$ , Unless Otherwise Noted)**

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
<b>STATIC</b>						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0V, I_D = 250\mu\text{A}$	25			V
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$	1	1.5	3	
Gate-Body Leakage	$I_{GSS}$	$V_{DS} = 0V, V_{GS} = \pm 20V$			$\pm 250$	nA
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS} = 20V, V_{GS} = 0V$			25	$\mu\text{A}$
		$V_{DS} = 20V, V_{GS} = 0V, T_J = 125^\circ\text{C}$			250	

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On-State Drain Current <sup>1</sup>	I <sub>D(ON)</sub>	V <sub>DS</sub> = 10V, V <sub>GS</sub> = 10V	70			A
Drain-Source On-State Resistance <sup>1</sup>	R <sub>DS(ON)</sub>	V <sub>GS</sub> = 10V, I <sub>D</sub> = 30A		7	9	mΩ
		V <sub>GS</sub> = 7V, I <sub>D</sub> = 24A		8	10	
Forward Transconductance <sup>1</sup>	g <sub>f</sub>	V <sub>DS</sub> = 15V, I <sub>D</sub> = 30A		16		S

**DYNAMIC**

Input Capacitance	C <sub>iss</sub>	V <sub>GS</sub> = 0V, V <sub>DS</sub> = 15V, f = 1MHz	2700			pF
Output Capacitance	C <sub>oss</sub>		500			
Reverse Transfer Capacitance	C <sub>rss</sub>		200			
Total Gate Charge <sup>2</sup>	Q <sub>g</sub>	V <sub>DS</sub> = 0.5V <sub>(BR)DSS</sub> , V <sub>GS</sub> = 10V, I <sub>D</sub> = 35A	25			nC
Gate-Source Charge <sup>2</sup>	Q <sub>gs</sub>		7			
Gate-Drain Charge <sup>2</sup>	Q <sub>gd</sub>		11			
Turn-On Delay Time <sup>2</sup>	t <sub>d(on)</sub>		7			
Rise Time <sup>2</sup>	t <sub>r</sub>	V <sub>DS</sub> = 15V, R <sub>L</sub> = 1Ω I <sub>D</sub> ≈ 30A, V <sub>GS</sub> = 10V, R <sub>GS</sub> = 2.5Ω	7			nS
Turn-Off Delay Time <sup>2</sup>	t <sub>d(off)</sub>		24			
Fall Time <sup>2</sup>	t <sub>f</sub>		6			

**SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS (T<sub>C</sub> = 25 °C)**

Continuous Current	I <sub>S</sub>	I <sub>F</sub> = I <sub>S</sub> , V <sub>GS</sub> = 0V		70		A
Pulsed Current <sup>3</sup>	I <sub>SM</sub>				170	
Forward Voltage <sup>1</sup>	V <sub>SD</sub>				1.3	V
Reverse Recovery Time	t <sub>rr</sub>	I <sub>F</sub> = I <sub>S</sub> , dI <sub>F</sub> /dt = 100A / μS		37		nS
Peak Reverse Recovery Current	I <sub>RM(REC)</sub>			200		
Reverse Recovery Charge	Q <sub>rr</sub>			0.043		

<sup>1</sup>Pulse test : Pulse Width ≤ 300 μsec, Duty Cycle ≤ 2%.<sup>2</sup>Independent of operating temperature.<sup>3</sup>Pulse width limited by maximum junction temperature.**REMARK: THE PRODUCT MARKED WITH “P70N02LS”, DATE CODE or LOT #**

**NIKO-SEM****N-Channel Logic Level Enhancement  
Mode Field Effect Transistor****P70N02LS  
TO-263 (D<sup>2</sup>PAK)****TO-263 (D<sup>2</sup>PAK) MECHANICAL DATA**

Dimension	mm			Dimension	mm		
	Min.	Typ.	Max.		Min.	Typ.	Max.
A	14.5	15	15.8	H	1.0	1.5	1.8
B	4.2		4.7	I	9.8		10.3
C	1.20		1.35	J		6.5	
D		2.8		K		1.5	
E	0.3	0.4	0.5	L	0.7		1.4
F	-0.102		0.203	M	4.83	5.08	5.33
G	8.5	9	9.5	N			

